ACTIVE (DIGITAL) DELAY LINES SERIES A0805 5-TAP 8-PIN DIP SERIES SA0805 5-TAP 8-PIN SIP SERIES A1405 5-TAP 14-PIN DIP SERIES A1410 10-TAP 14-PIN DIP

- Economical cost, prompt delivery!
- Wide variety of sizes and values
- Choice of 5 or 10 equally spaced taps
- TTL and DTL compatible
- Operating temperature: 0°C to 70°C
- Excellent for applications requiring high delay stability, fast rise times and no jitter, such as memory boards, disk drives, and signal processing.

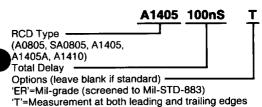
OPTIONS

- Non-standard delay times or tolerances
- Non-symmetrical tap delays
- Dynamic RAM timing delay
- Faster rise times
- ECL, H-CMOS, and low power designs avail.
- Measurement at both leading and trailing edges
- Ceramic IC's screened to MIL-STD-883, -55 to +125°C per MIL-D-83532 (Option 'ER')
- Fast logic TTL available

Total Delay	Delay Per Tap (nSec)	
	A0805, SA0805, A1405	A1410
20	4	*
25	5	*
30	6	
40	8	*
50	10	5
60	12	6
75	15	7.5
100	20	10
125	25	12.5
150	30	15
175	35	17.5
200	40	20
250	50	25
300	60	30
350	70	35
400	80	40
450	90	45
500	100	50
750	150	75
1000	200	100

* Consult factory for availability.

HOW TO ORDER











Wide selection of sizes!

RCD's digital delay lines have been designed to provide precise tap delays with all the necessary drive and pickoff circuitry. All inputs and outputs are schottky-type and require no additional components to achieve the specified delays. Encapsulated/molded construction ensures full compliance to all applicable requirements of Mil-D-23859. Units are 100% inspected for solder joint integrity and electrical conformance.

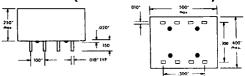
ELECTRICAL CHARACTERISTICS

Total Delay Tol.: ±5 or 2nS whichever is greater Tap Delay Tol.: ±5 or 2nS whichever is greater Insulation Resistance: 1000MΩ min.

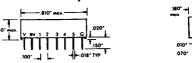
Dielectric Strength: 100VDC

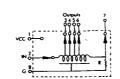
Rise Time: 4nS max.

TYPE A0805 (Available 20nS to 500nS)



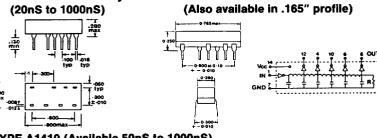
TYPE SA0805 (Available 20nS to 250nS)



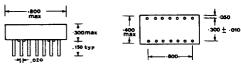


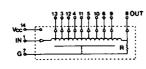
TYPE A1405A - Auto insertable molded

TYPE A1405 - Economy (20nS to 1000nS)



TYPE A1410 (Available 50nS to 1000nS)





TEST CONDITIONS @25°C

- 1) Delay measured at 1.5V on leading edge only with no loads on output.
- 2) Rise time measured from 0.75V to 2.4V
- 3) Delay will inversely vary approximately 4% for every 5% change in supply voltage.
- 4) Supply voltage (VCC)=5.0±.25VDC
- 5) Input test pulse: 3.2V, 2nS rise time, width>40% of total delay, pulse period to be a minimum of 3× the pulse width

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